

## Regional NEWS

1310 Madison Wisconsin Section, By Jay L. Bucher

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1310 Madison Wisconsin Section Meeting.



Twenty five people were in attendance at the Madison Wisconsin Section meeting held at Covance, Inc., in Madison, Wisconsin. Covance's Metrology Department sponsored the meeting and provided outstanding facilities.

The meeting got started by the Madison Section coordinator, Jay Bucher, who welcomed everyone, and opened the meeting by having all the attendees give their name, company and what they do. After the introductions, the program got underway.

Our first presenter was Dilip Shah from E = mc<sup>3</sup> Solutions, (NCSLI Marketing Liaison-164.2), again continued to break what we believe to be new ground, with the assistance of Don Navis and Covance, in doing presentations at an NCSLI section meeting without having to be physically present . . . Web 2.0 Dilip's presentation "Establishing reverse metrological traceability," was very informative, and showed how to make one's way backwards from their test equipment to the SI via different vendors and their NMIs. We followed Dilip's Powerpoint and audio presentation on the screen at Covance in Madison, while Dilip was coming to us from California. Through a telephone hook up, we could ask questions and exchange information in real time. Quite the way to communicate and educate in the 21st Century. There can be no doubt that this form of making presentations is the wave of the future - in reducing travel and hotel costs, dealing with inclement weather conditions, and time/business constraints. Thanks again to Dilip and Don for continuing to set the bar at a new level.

After Dilip's presentation, and a short break, we had a round table discussion on "Integrating metrology into the purchasing of test equipment," with Don Navis and Kurt Waldmer from Covance and Jay Bucher from Bucherview Metrology Services sitting on the panel. Dilip did not take up his full time, so what was left over was consumed along with the allotted time by this

very active discussion. With the enthusiasm of all the attendees, there can be no doubt that round table discussions will be a part of future section meetings. Not only were there great questions, but varied opinions and experiences expressed by all participants. That clapping you hear in the background is the panel expressing their gratitude to the entire group. Well done.

After taking a group picture, having our usual 100 % recipient door prize drawing, and lunch, Andy Duchaine from JH Metrology Co., Inc., gave a presentation on "Partnering with 3rd party calibration laboratories." Andy's perspective as both a calibration provider, and a calibration technician gave a different view for the attendees, and hopefully helped everyone better understand that this is an important part of any quality calibration program. Thanks, Andy, for making the pros and cons more visible for those that have only seen the situation from their side.

Then Michael Byrnes from the American Society for Quality gave a presentation on "ASQ test development process." For those in attendance that already have their CCT (Certified Calibration Technician), they were now enlightened as to the process and procedures used to develop and maintain a certification from start to finish, plus what went into the five year review process for all ASQ certifications. As a certification developer, Michael knows first-hand what goes into the process, and how much the volunteers bring to each and every workshop, rather its for writing, reviewing or surveying the field. Thanks, Michael, for the broad overview, and very informative presentation.

Our next section meeting will be in the fall of 2010, and we look forward to seeing everyone again. Thanks go out to Bucherview Metrology Services and JH Metrology Co., Inc. for providing the door prizes for all in attendance. And thanks, again, for Dilip and his willingness to advance our learning and education abilities via his on-line presentation.